In the Specification:

Please make the following changes at the indicated locations in the specification:

Page 7, lines 21 to 26, please make the following changes in the paragraph between these lines:

With the method according to the present invention, it is now possible to determine fluorescences, the wavelengths of which are close to the excitation wavelength. This is particularly significant for the use of optical elements in photolithography, since the energy of fluorescence at wavelengths of this type is also sufficient to expose the photosensitive resist of a wafer ~~waver~~, which results in a strong loss of contrast in the circuit pattern projected onto the wafer.

Page 8, line 26, please insert the following:

BRIEF DESCRIPTION OF THE DRAWING

The following sole figure is a diagrammatic representation of a preferred device for carrying out the method of determining the suitability of a crystalline optical material, especially an alkali or alkaline earth halide crystal, for making an optical element, especially an optical element for photolithograph.

Page 8, line 27, to page 9, line 17, please make the following changes in the paragraph between these lines:

The present invention also relates to a device for carrying out a particularly preferred method according to the present invention. A device of this type includes a radiation source, especially a pulsed laser 10, for transmitting excitation radiation at an excitation wavelength, a sample holder 30 for holding a material sample to be determined, and a device for measuring ~~determining a~~ fluorescence intensities of fluorescence induced in the material sample by the excitation radiation ~~wavelength~~. The excitation radiation ~~wavelength~~ travels along a typically linear beam path that starts at the radiation source, through the material sample, and preferably enters a reference photodiode. According to the present invention, the fluorescence determination device is located outside this beam path, so that no radiation of the excitation wavelength can strike the fluorescence determination device directly. The device is preferably arranged such that the fluorescence to be measured describes a fluorescence beam path that extends perpendicularly to the excitation beam path. The fluorescence measurement device typically includes one or more optical lenses that bundle the fluorescence emitted by the material sample to be investigated in a polychromator and/or a grating spectrograph 20. The fluorescent light that is broken down into its individual wavelengths in the spectrograph is then deflected to a CCD camera 25, in particularly an I-CCD, in which the intensities at ~~intensity of~~ the individual wavelengths are [[is]] determined and are preferably processed ~~is preferably processes~~ and stored using a computer 50 and/or a data processing system. The fluorescence intensities ~~points~~ determined and stored in this manner

using the CCD camera can [[now]] be easily compared with stored standard values and analyzed by ~~determined in~~ the computer.

Page 9, lines 19 to 28, please make the following changes in the paragraph between these lines:

The device according to the present invention is unique in that a barrier element is located between the material sample to be tested and the CCD camera that prevents the high-energy excitation radiation ~~wavelength~~ from passing through to the CCD camera. The ~~By way of the~~ barrier element located in the device according to the present invention[[,]] ~~it is ensured~~ insures that no light from the radiation source reaches the CCD camera. The barrier element also prevents scattered light from the excitation wavelength from reaching the CCD camera, which could not only falsify the measurement but also destroy this highly sensitive camera. The barrier element used according to the present invention should not fluoresce itself at the excitation wavelengths and thereby falsify measured fluorescent values.

Page 9, line 30, to page 10, line 6, please make the following changes in the paragraph between these lines:

All types of devices that deflect, reflect or absorb a certain wavelength are suitable for use as the barrier element. The simplest configuration is an optical grating, for example, as included in a polychomator and/or spectrographs. In a further preferred exemplary embodiment according to the present invention, the

barrier element includes a wavelength-specific filter 40, in particular a multilayer filter, in the case of which a double layer or multiple reflective layers are applied that blank out or reflect the particular wavelength. A particularly preferred filter is a dielectric thin-layer filter.